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1 Board level reliability testing of μ BGA^(R) packaging with lead-free solder attachment
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Pages:10 - 14

[\[Abstract\]](#)
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[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) IEEE CNF

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L2	75	hsiao-k\$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:37
L3	1	hsiao-k\$-t\$.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:37
L4	25090	test\$4 near3 memory	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:38
L5	18780	test\$4 near2 memory	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:38
L6	3983	(test\$4 near2 memory) same (microprocessor or CPU or computer or server or processor)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:40
L7	1036	(test\$4 near2 memory) and (signal near10 receiv\$4 near10 (microprocessor or CPU or computer or server or processor))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:41
L8	481	(test\$4 near2 memory) and (((clock\$1 adj2 signal\$1) near10 (microprocessor or CPU or computer or server or processor))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:43
L9	13855	((clock\$1 adj2 signal\$1) near10 (microprocessor or CPU or processor))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:44
L10	77	(((((clock\$1 adj2 signal\$1) near10 (microprocessor or CPU or processor)))) same compar\$5 same test\$3	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:45
L11	2	(((((clock\$1 adj2 signal\$1) near10 (microprocessor or CPU or processor)))) same compar\$5 same test\$3 same sort\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:56
L12	2	(((((test\$4 adj2 signal\$1) near10 (microprocessor or CPU or processor)))) same compar\$5 same sort\$3	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:57
L13	5	(((((test\$4 adj2 signal\$1) same (microprocessor or CPU or processor)))) same compar\$5 same sort\$3	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 15:58

L14	0	(microprocessor near10 compar\$5 near10 sort\$3) same (test\$4 near2 (data or information or script\$1 or signal\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:00
L15	6	(microprocessor same compar\$5 same sort\$3) same (test\$4 near2 (data or information or script\$1 or signal\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:01
L16	147	compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:02
L17	34	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) and l4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:02
L18	12	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) same l4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:02
L19	1	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) and l4 and (714/718.ccls.)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:04
L20	4	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) and l4 and (365/201.ccls.)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:04
L21	0	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) and l4 and (324/765.ccls.)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:04
L22	0	(compar\$5 same sort\$3 same (test\$4 near2 (data or information or script\$1 or signal\$1))) and l4 and (324/763.ccls.)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/03/11 16:04